

OBJECTIVE

Dynax

DF1G0010-16N

RF GaN POWER AMPLIFIER for Wireless Infrastructure

DF1G0010-16N is a 12.5 W RF GaN HEMT Transistor with first generation RF GaN technology from Dynax, which is ideal for 20 MHz to 1000 MHz ultra wideband applications. It features fully input matching.

Applications

- Wideband or Narrowband Amplifiers
- Test Instrumentations

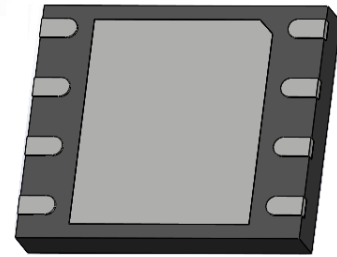
Typical RF Performance ¹

- Frequency: 20 – 1000 MHz
- Saturation Output Power: 12.5 W
- Saturation Drain Efficiency: 66% @650MHz
- Small Signal Gain: 18 dB @650MHz

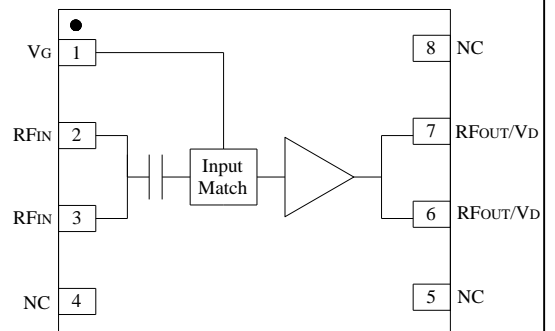
Note:

¹ Typical Performance in Dynax DF1G0010-16N Class AB Demo with the device soldered onto the heatsink, test condition: $V_{DD} = 28\text{ V}$, $I_{DQ} = 90\text{ mA}$, Input signal Pulsed CW, Pulse Width = 100 μs , Duty Cycle = 10 %.

20 – 1000 MHz, 12.5 W,
RF GaN POWER AMPLIFIER



Package Type: DFN 6×5mm



(Top View)
Figure 1. Pin Connection

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Table 1. Maximum Ratings

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V _{DSS}	150	V
Gate-Source Voltage	V _{GS}	-10 ~ +2	V
Operating Voltage	V _{DD}	0 ~ +55	V
Maximum Forward Gate Current	I _{GMAX}	3.2	mA
Storage Temperature Range	T _{STG}	-65 ~ +150	°C
Operating Junction Temperature	T _J	225	°C
Absolute Maximum Channel Temperature ²	T _{MAX}	275	°C

²Functional operation above 225°C has not been characterized and is not implied. Operation at T_{MAX} (275°C) reduces median time to failure by an order of magnitude; Operation beyond T_{MAX} could cause permanent damage.

Table 2. Thermal Characteristics

Parameter	Symbol	Value	Unit
Thermal Resistance at Average Power by Infrared Measurement, Active Die Surface-to-Case T _{base-plate} = 85°C, P _D = TBD	R _{thjc(IR)}	TBD	°C/W
Thermal Resistance at Average Power by Finite Element Analysis, Junction-to-Case T _{base-plate} = 85°C, P _D = TBD	R _{thjc(FEA)}	TBD	°C/W

Table 3. Ordering Information

Device	Package Type	Marking
DF1G0010-16N	DFN 6×5mm	DU16A

Table 4. Bias Sequences

Bias-up Sequence	Bias-down Sequence
Set V _{GS} to -5 V	Turn off RF power
Turn on V _{DS} to 28 V	Reduce V _{DS} down to 0 V
Increase V _{GS} until I _{DS} current is attained	Turn off V _{GS}
Apply RF input power	

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Table 5. Electrical Characteristics ($T_A = 25\text{ }^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min.	Typ.	Max.	Unit
DC Characteristics (measured on wafer prior to packaging)					
Drain-Source Leakage Current ($V_{GS} = -10\text{ V}$, $V_{DS} = 150\text{ V}$)	I_{DSS}	-	-	3.2	mA
Drain-Source Breakdown Voltage ($V_{GS} = -10\text{ V}$, $I_D = 3.2\text{ mA}$)	$V_{(BR)DSS}$	150	-	-	V
Gate Threshold Voltage ($V_{DS} = 28\text{ V}$, $I_D = 3.2\text{ mA}$)	$V_{GS(th)}$	-4.0	-3.2	-1.0	V
Gate Quiescent Voltage ($V_{DD} = 28\text{ V}$, $I_D = 90\text{ mA}$)	$V_{GS(Q)}$	-	-3.0	-	V
RF Characteristics					
Typical Performance ³					
Saturation Output Power	P_{sat}	-	12.5	-	W
Saturation Drain Efficiency	η_D	-	66	-	%
Power Gain	G_P	-	18	-	dB
Gain Flatness	G_F	-	3	-	dB

³ Typical Performance in Dynax DF1G0010-16N Class AB Demo with the device soldered onto the heatsink, test condition: $V_{DD} = 28\text{ V}$, $I_{DQ} = 90\text{ mA}$, $f = 20 - 1000\text{ MHz}$, Input signal Pulsed CW, Pulse Width = $100\text{ }\mu\text{s}$, Duty Cycle = 10 %.

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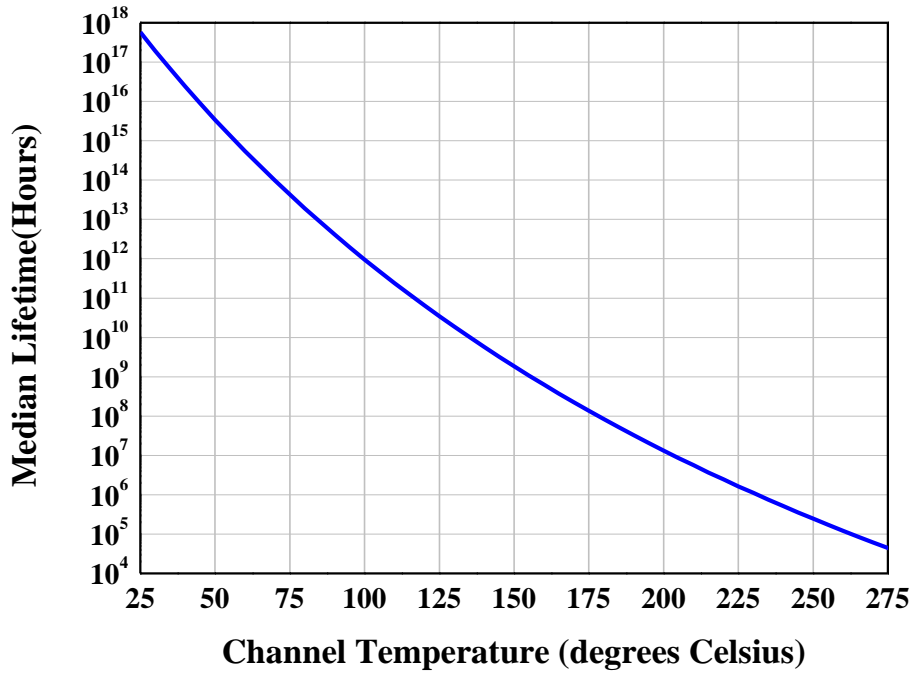
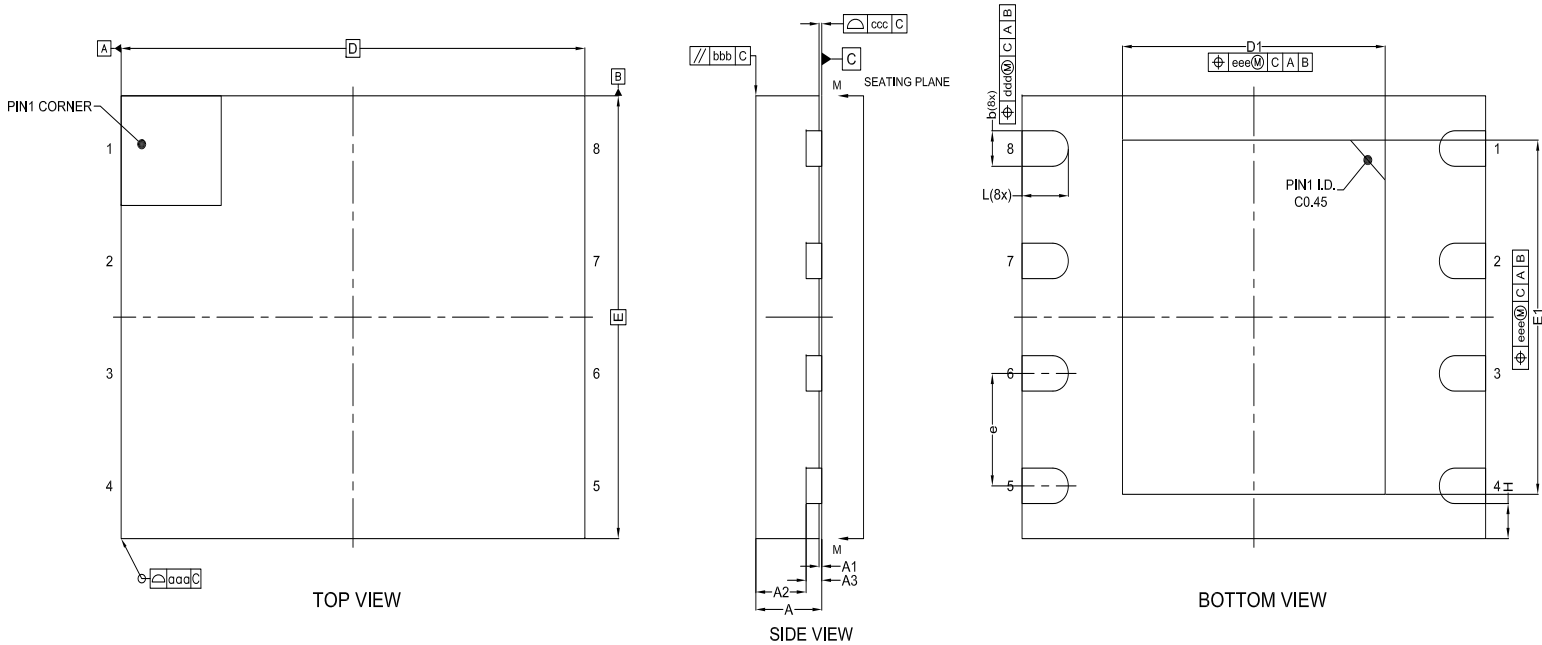


Figure 2. Median Lifetime vs. Channel Temperature

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Package Dimensions

Package Type: DFN 6x5mm



DESCRIPTION	SYMBOL	MILLIMETER			
		MIN	NOM	MAX	
TOTAL THICKNESS	A	0.80	0.85	0.90	
STAND OFF	A1	0.00	---	0.05	
MOLD THICKNESS	A2	0.60	0.65	0.70	
L/F THICKNESS	A3	0.203 REF			
BODY SIZE	X	D	5.90	6.00	6.10
	Y	E	4.90	5.00	5.10
LEAD PITCH	e	1.27 BSC			
LEAD WIDTH	b	0.35	0.40	0.45	
LEAD LENGTH	L	0.55	0.60	0.65	
EP SIZE	X	D1	3.35	3.40	3.45
	Y	E1	3.95	4.00	4.05
LEAD EDGD TO PKG EDGE	H	0.395 BSC			
TOLERANCE OF FORM AND POSITION					
GEOMETRIC TOLERANCE	aaa	0.10			
MOLD FLATNESS	bbb	0.10			
LEAD COPLANARITY	ccc	0.08			
LEAD POSITION OFFSET	ddd	0.10			
EXPOSED PAD OFFSET	eee	0.10			

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Product Documentation and Software

Refer to the following resources to aid your design process.

Application Notes

- AN_02: User Guide for GaN HEMT Transistor

Document Revision History

The following table summarizes revisions to this document.

Status	Revision	Date	Description
Objective datasheet	V01	08/23/2021	Initial version.
Objective datasheet	V02	11/04/2021	Update typical RF performance and POD drawing.

Abbreviations

Acronym	Description
CW	Continuous Waveform
GaN	Gallium Nitride
HEMT	High Electron Mobility Transistor
MTTF	Median Time To Failure
VSWR	Voltage Standing-Wave Ratio

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Disclaimer

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